

INCH-POUND

MIL-PRF-55339B
AMENDMENT 2
24 February 1998
SUPERSEDING
AMENDMENT 1
4 FEBRUARY 1997

PERFORMANCE SPECIFICATION
ADAPTERS, CONNECTORS, COAXIAL, RADIO FREQUENCY,
(BETWEEN SERIES AND WITHIN SERIES),
GENERAL SPECIFICATION FOR

This amendment forms a part of MIL-PRF-55339B, dated 1 April 1996, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 1

Delete and substitute new Beneficial comments block as follows:

Beneficial comments (recommendations, additions, deletions) and any pertinent data which may be of use in improving this document should be addressed to: Defense Supply Center Columbus, ATTN: DSCC-VAI, 3990 East Broad Street, Columbus, Ohio 43216-5000.

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* 4.5.2.1.1, line 3: Delete "or not less than once every year" and substitute "or not less than once every three years".

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* TABLE VII: Delete and substitute as shown on page 2 of this amendment.

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"TABLE VII. Group C inspection. 1/

Inspection	Requirement paragraph	Test method paragraph
<u>Subgroup 1</u>		
VSWR	3.12	4.6.9
RF leakage 2/	3.13	4.6.10
RF insertion loss 2/	3.14	4.6.11
Durability	3.15	4.6.12
Force to engage/disengage	3.6	4.6.3
Coupling proof torque	3.7	4.6.4
Mating characteristics	3.8	4.6.5
VSWR	3.12	4.6.9
Dielectric withstanding voltage	3.16	4.6.13
<u>Subgroup 2</u>		
Contact resistance (center and outer contacts)	3.17	4.6.14
Vibration, high frequency 2/	3.18	4.6.15
Contact resistance (center contact)	3.17	4.6.14
Shock (specified pulse) 2/	3.19	4.6.16
Contact resistance (center contact)	3.17	4.6.14
Dielectric withstanding voltage	3.16	4.6.13
Contact resistance (center contact)	3.17	4.6.14
Thermal shock (hermetic- sealed adapters)	3.20	4.6.17
Dielectric withstanding voltage	3.16	4.6.13
Contact resistance (center contact)	3.17	4.6.14
Moisture resistance	3.21	4.6.18
Dielectric withstanding voltage	3.16	4.6.13
Corona level 2/	3.22	4.6.19
Hermetic Seal	3.10	4.6.7
Leakage	3.10.1	4.6.7.1
RF high potential withstanding voltage 2/	3.23	4.6.20
Corrosion (salt spray)	3.24	4.6.21
Force to engage/disengage	3.6	4.6.3
Coupling mechanism retention force	3.25	4.6.22
Force to engage/disengage	3.6	4.6.3

1/ Manufacturers who have products listed on QPL-39012 and produce adapters of the same series, may apply to the qualifying activity for waiver in performing group C, subgroup 2, retention testing, providing the interfacial coupling, materials, and plating of the adapter and connectors are identical.

2/ These tests are to be performed during initial qualification only, as long as the qualifying design, materials, and manufacturing process has not been changed."

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The margins of this amendment are marked with asterisks to indicate where changes from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous amendment.

CONCLUDING MATERIAL

Custodians:

Army - CR
Navy - EC
Air Force - 85
NASA - NA

Preparing activity:

DLA - CC

(Project 5935-4122)

Review activities:

Army - AR, AT, MI
Navy - AS, MC, OS, SH
Air Force - 19, 99